



1FW 2881-
PATENT
8053-1008

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Yuichi NAITOU et al.

Conf. 7712

Application No. 09/981,390

Group 2881

Filed October 18, 2001

Examiner P. Johnston

SCANNING PROBE MICROSCOPE WITH
PROBE FORMED BY SINGLE CONDUCTIVE
MATERIAL

AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

May 17, 2004

Sir:

In response to the Official Action mailed January 16, 2004, for which the period for response has been extended one month, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks begin on page 21 of this paper.